

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L23	0	((built-in self test or self test device or BIST or in-circuit test) AND integrated circuit AND (external tester or ATE or external testing device or external test terminal) AND test result AND evaluation circuit).dm.	US-PGPUB; USPAT; USOCR	ADJ	ON	2008/04/26 16:40

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